

Supplementary Materials for

Elastic and electronic tuning of magnetoresistance in MoTe₂

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Supporting Online Material

XRD for MoTe₂ single crystals.

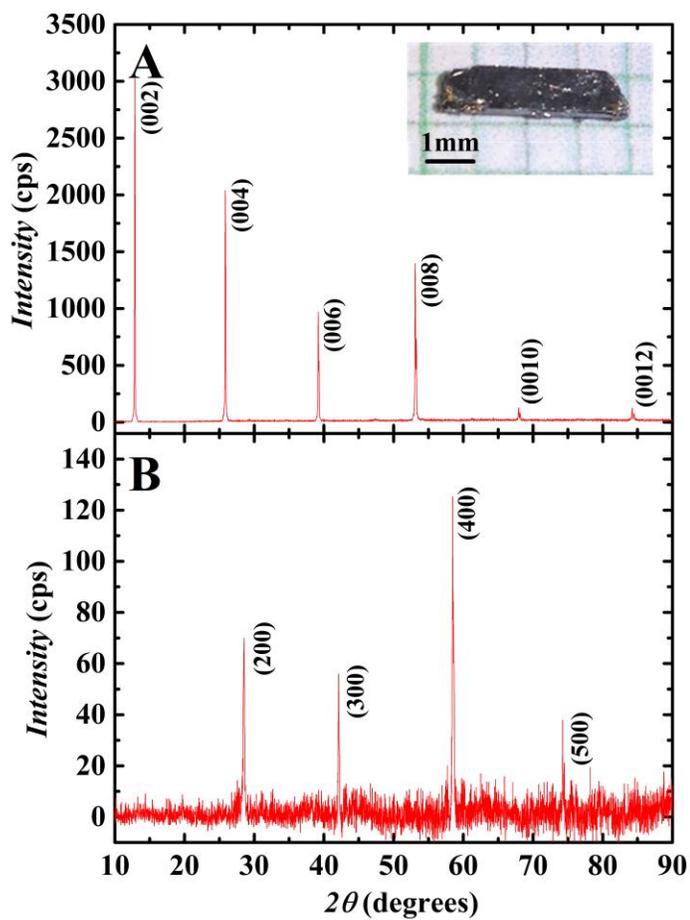


fig. S1. XRD for MoTe₂ single crystal. XRD of MoTe₂ single crystals aligned along: (a) (00L) and (b) (H00). The inset in A is a picture of a MoTe₂ single crystal.

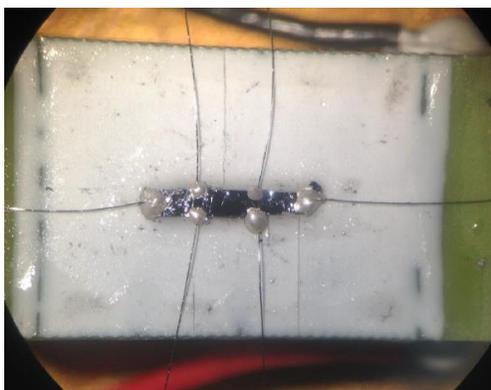


fig. S2. MoTe₂ crystal on the piezoelectric stack.

SMR of different samples.

Figure S3 shows the electrical transport data under different strain for two different samples. All results were measured at 2 K, and the strain was applied along the b direction. SMR is defined as $SMR = \frac{[R(\epsilon,H)-R(\epsilon,0)]-[R(0,H)-R(0,0)]}{R(0,0)} \times 100\%$. Figs. S3 A and B are plots of the resistance vs magnetic field. Figs. S3 C and D show the calculated SMR as a function of magnetic field for the two samples. As it can be seen from figs. S3 C and D, the strain effect mainly appears at high magnetic fields and varies with sample. Sample 2 exhibits a much bigger strain effect than sample 1. Fig. S4 are plots of the electrical transport data under different strain, with strain applied along a for two different samples. The strain effect mainly appears at high magnetic fields and varies with sample. Sample 4 exhibits a much bigger strain effect than sample 3.

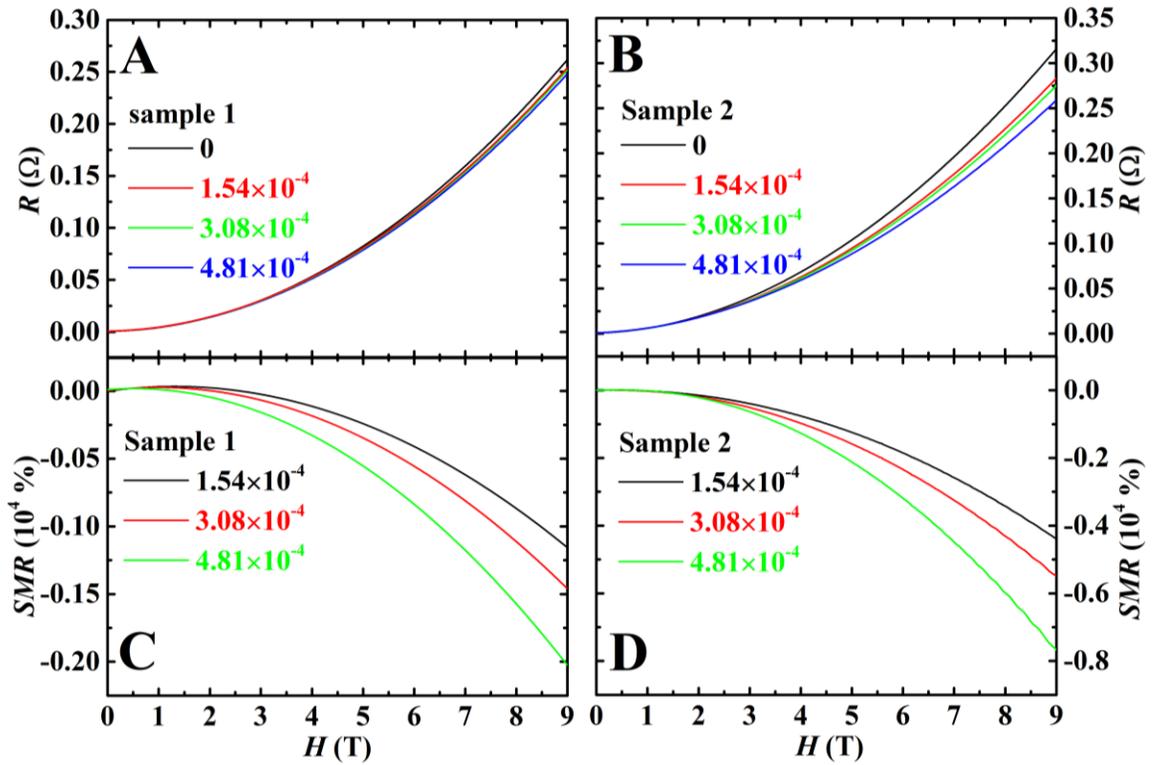


fig. S3. Transport and SMR data on samples 1 and 2. Electrical transport data measured at 2 K for two different samples: (A), R - H curves under different strain for sample 1, (B) R - H curves under different strain for sample 2, (C) SMR as a function of magnetic field for sample 1 and (D) SMR as a function of magnetic field for sample 2. Strain was applied along b direction.

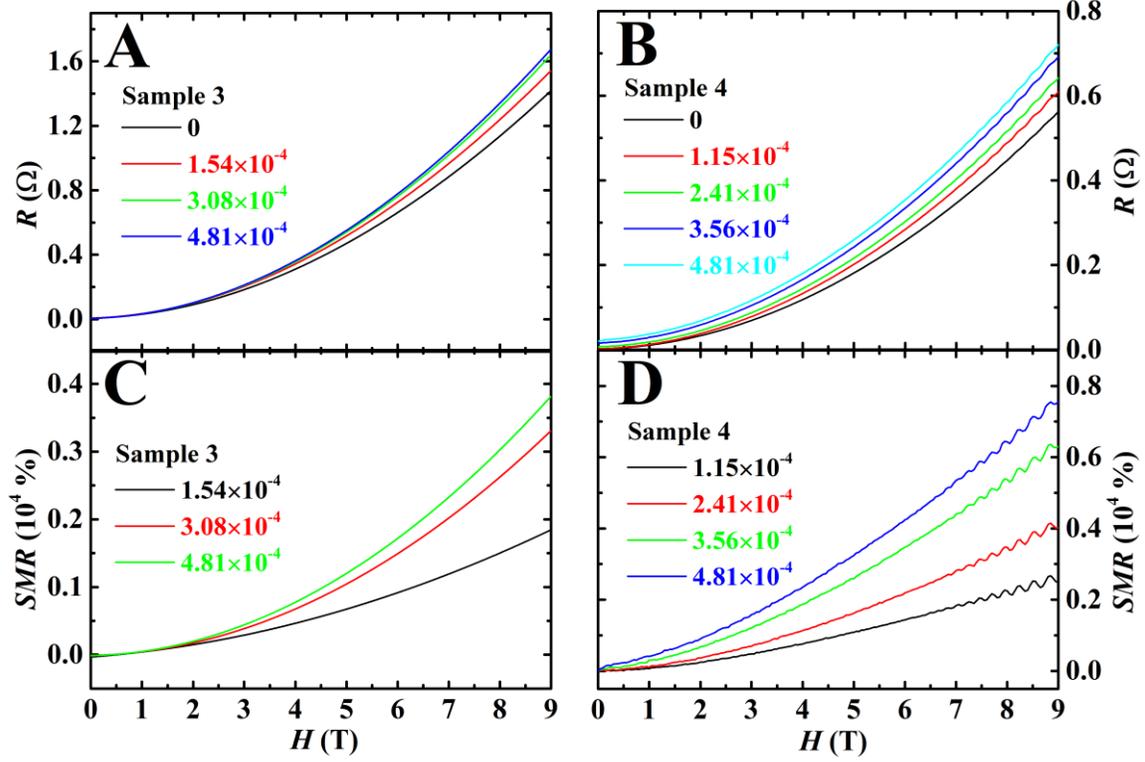


fig. S4. Transport and SMR data on samples 3 and 4. Electrical transport data measured at 2 K for two different samples: (A), R - H curves under different strain for sample 3, (B) R - H curves under different strain for sample 4, (C) SMR as a function of magnetic field for sample 3 and (D) SMR as a function of magnetic field for sample 4. Strain was applied along a direction.

Hall Effect and Two-band model fitting

Figure S5 shows the results of the Hall effect and the two-band model fitting. The electrical transport data was measured at 2 K with strain applied along the b direction. Figs. S5 A and B show the Hall conductivity $\sigma_{xy} = -\rho_{xy}/(\rho_{xy}^2 + \rho_{xx}^2)$ and the longitudinal conductivity $\sigma_{xx} = \rho_{xx}/(\rho_{xy}^2 + \rho_{xx}^2)$ measured without strain. According to the two-band model (29, 39-41), the Hall conductivity is $\sigma_{xy} = \left[\frac{n_e \mu_e^2}{1 + (\mu_e \mu_0 H)^2} - \frac{n_h \mu_h^2}{1 + (\mu_h \mu_0 H)^2} \right] e \mu_0 H$, and the longitudinal conductivity is $\sigma_{xx} = \frac{n_e e \mu_e}{1 + (\mu_e \mu_0 H)^2} + \frac{n_h e \mu_h}{1 + (\mu_h \mu_0 H)^2}$. The red lines shown in figs. S5 A and B are the fitting curves. Figs. S5 C-F show the extracted carrier density, n , and mobility, μ_e for electrons and μ_h for holes. Both carrier density and mobility decrease with increasing strain when strain is applied along the b direction.

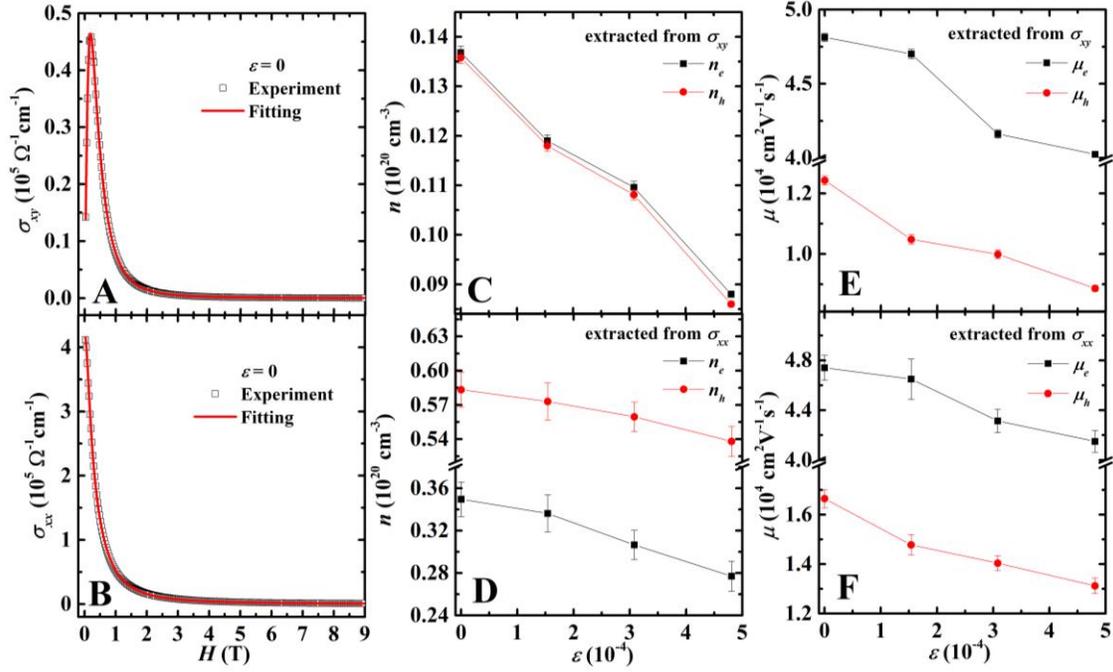


fig. S5. Conductivity, carrier density, and mobility with and without strain. (A) Hall conductivity σ_{xy} and (B) the longitudinal conductivity σ_{xx} measured without strain at 2 K. (C) Electron and hole densities extracted from the fitting of σ_{xy} , (D) electron and hole densities extracted from the fitting of σ_{xx} , (E) electron and hole mobilities extracted from the fitting of σ_{xy} and (F) electron and hole mobilities extracted from the fitting of σ_{xx} . Strain was applied along b direction.

Strain vs Voltage

table S1. The piezoelectric stack shows an almost linear behavior in the voltage range of 0 to 150 V. Hence, we used the maximum response of the piezoelectric stack at 150 V to estimate the strain values for different voltages: $\varepsilon = \varepsilon_{max} \times V / 150$. $\varepsilon_{max} = 14.44 \times 10^{-4}$.

Voltage (V)	12	16	25	32	37	50
Strain (10 ⁻⁴)	1.15	1.54	2.41	3.08	3.56	4.81